

Between sessions, attendees take the opportunity to review research presentations at the 5th International Union of Materials Research Societies International Conference in Asia (IUMRS-ICA), held in Bangalore, India, October 13–16, 1998.

Symposium J on Polymers covered a wide range of topics including frontier areas of organic materials science such as fabrication of complex surfaces, patterns, conducting polymers, polymer surfaces, light-emitting materials, polymer electrolytes, electrical and dielectric properties of materials, polymer blends, high-

performance polymers, and polymers in nonlinear optical applications.

Characterization and Modeling

Symposium W, Computer-Aided Design of Materials, showed state-of-the-art calculations, for instance, using multimillion atom molecular dynamics simulations and *ab initio* materials design using supercomputing technology. These and other approaches were used to examine dislocations and fraction, dynamics of stick-slip in frictional sliding, as well as simulation of field-effect solar cells.

Symposium V, Characterization of Materials, covered an array of techniques including nuclear magnetic resonance, high-resolution electron microscopy, convergent beam electron diffraction, electron energy loss spectroscopy, Rutherford backscattering spectrometry, and electron probe microanalyzer. The techniques were examined in detail, and their use for understanding composites, defect structures, quasicrystals, and superconducting materials were elucidated. Phase transformation studies in titanium base alloys, chemistry associated with $\text{Li}_2\text{B}_8\text{O}_{13}$ and sinterability of UO_2 and other problems associated with silica aerogels were some of the other important topics.

Materials Education

A panel discussion in Symposium X, Materials Education, looked at the status of materials education in India and

assessed the needs for the future. The need for interdisciplinarity seems to be established, with agreement that this must continue. Also, the notion that research is global has a strong foothold in the Indian community, so the level of education and research efforts allows global collaboration and competition. Much of the focus, however, was on the need for a stronger connection to industry. Students tend to learn theory at the expense of more practical skills, bringing a large disconnect between student education and industry needs. An additional problem in India arises: Because the materials industry in certain areas may not yet exist locally, such as a semiconductor industry, industrial connections are difficult to achieve. Often, participants said, what the universities think is good for industry conflicts with what industry thinks it needs. This makes employability of graduates a problem.

The Indian Academy of Sciences will publish a special issue of the *Bulletin of Materials Sciences* containing the invited talks presented at the IUMRS-ICA-98 Conference. The contributed papers have also been forwarded to the journal for publication consideration.

Contributions made by
S. V. SUBRAMANYAM
GENERAL SECRETARY OF MRS-I



MRS NEWS


MRS Seeks Nominees for Outstanding Young Investigator Award, 2000

The Materials Research Society is accepting nominations for the Outstanding Young Investigator Award to be announced at the 2000 MRS Spring Meeting in San Francisco. The award is intended to recognize outstanding, interdisciplinary scientific work in materials research by a young scientist or engineer. The award recipient must also show exceptional promise as a developing leader in the materials area. The award consists of a \$3,000 cash prize, a presentation trophy bearing a brief citation, and a certificate.

Previous recipients are Stuart S.P. Parkin (IBM) contributions in new materials, high T_c superconductors, and magnetic multilayers displaying oscillatory exchange coupling; David D. Awschalom (University of California—Santa Barbara) for contributions to the field of nanostructured materials; Charles M. Lieber (Harvard University) for contributions to the understanding of

novel materials through synthesis and elegant determination of complex local structure and electronic properties; David J. Eaglesham (AT&T Bell Laboratories) for creativity, leadership, and experimental ingenuity in discovery and understanding of fundamental interface, surface, and defect phenomena in semiconductor crystal growth; A. Paul Alivisatos (University of California—Berkeley) for leadership in materials research, notably in the field of nanocrystals; Antonios G. Mikos (Rice University) for the synthesis and processing of new biomaterials for tissue engineering, supports for cells, tissue-growth conduits, targeted cell-adhesion substrates, and cellular-response stimulants; Christopher N. Bowman (University of Colorado) for seminal contributions to the field of highly crosslinked polymers, information storage materials, and computational methods in polymerization engineer-

ing; Anne M. Mayes, (Massachusetts Institute of Technology) for incisive theoretical and experimental investigations of macromolecules at and near surfaces and interfaces leading to tailorable surface properties, especially novel biocompatible substrates; and Chad A. Mirkin (Northwestern University) for his pioneering and leadership role in identifying, establishing, and developing a new interdisciplinary field that focuses on using complex biological macromolecules to assemble inorganic nanoparticle building blocks into functional meso- and macroscopic structures.

The deadline for submission of nominations is October 1, 1999. Guidelines and application forms are available from website www.mrs.org/awards/ or from John B. Ballance, Executive Director, Materials Research Society, MRS Headquarters, Materials Research Society, 506 Keystone Drive, Warrendale, PA 15086, USA. 



April 24 - April 28
San Francisco, California

Exhibit:
April 25-27

2000 MRS Spring Meeting Chairs

Anna C. Balazs
University of Pittsburgh
Department of Chemical Engineering
1231 Benedum Hall
Pittsburgh, PA 15261
Tel 412-648-9250
Fax 412-624-9639
balazs@vms.cis.pitt.edu

Robert Q. Hwang
Sandia National Laboratories
MS 9161
P.O. Box 969
Livermore, CA 94551
Tel 925-294-1570
Fax 925-294-3231
rghwang@sandia.gov

Kevin S. Jones
University of Florida
Department of Materials Science and Engineering
525 Engineering Building
P.O. Box 116130
Gainesville, FL 32611-6400
Tel 352-392-9872
Fax 352-392-8381
kjones@eng.ufl.edu

Frances M. Ross
IBM T.J. Watson Research Center
Room 29-019
P.O. Box 218
Yorktown Heights, NY 10598
Tel 914-945-1022
Fax 914-945-2141
fmross@us.ibm.com

call for papers

Abstract Deadlines:

October 18, 1999 for abstracts sent via e-mail, fax, or mail
November 1, 1999 for abstracts sent via the MRS Web site

In fairness to all potential authors, late abstracts will not be accepted.

SYMPOSIA and SYMPOSIUM ORGANIZERS

A: Amorphous and Heterogeneous Silicon Thin Films—2000
Howard M. Branz, National Renewable Energy Laboratory, Tel 303-384-6694, Fax 303-384-6531, hbranz@nrel.gov; **Robert W. Collins**, The Pennsylvania State University, Tel 814-865-3059, Fax 814-865-2326, rwc6@psu.edu; **Subhendu Guha**, United Solar Systems Corporation, Tel 248-362-3120, Fax 248-362-4442, sguha@mail.ic.net; **Hiroaki Okamoto**, Osaka University, Japan, Tel 81-6-8506315, Fax 81-6-8506316, okamoto@ee.es.osaka-u.ac.jp; **Martin Stutzmann**, Technische Universität München, Germany, Tel 49-89-28912760, Fax 49-89-28912737, stutz@wsi.tum.de; Administrative contacts: **Mary Ann Woolf** and **P. Craig Taylor**, University of Utah, Tel 801-581-4246, Fax 801-581-4246 or -4801, woolf@physics.utah.edu

B: Si Front-End Processing—Physics and Technology of Dopant-Defect Interactions II
Aditya Agarwal, Eaton Corporation, Tel 978-232-4264, Fax 978-232-4200, aagarwal@bev.etn.com; **Lourdes Pelaz**, Universidad de Valladolid, Spain, Tel 34-983-423710 x-25502, Fax 34-983-423675, lourdes@ele.uva.es; **Hong-Ha Vuong**, Lucent Technologies, Bell Laboratories, Tel 908-582-6692, Fax 908-582-4228, vuong@bell-labs.com; **Paul Packan**, Intel Corporation, Tel 503-613-9869, Fax 503-613-8950, ppackan@ptdcs2.intel.com; **Masataka Kase**, Fujitsu Ltd., Japan, Tel 81-584-241571, Fax 81-594-241566, m_kase@pe.mie.ed.fujitsu.co.jp

C: Gate Stack and Silicide Issues in Silicon Processing
Larry Clevenger, IBM Microelectronics, Tel 914-892-9019, Fax 914-892-9068, lacleven@us.ibm.com; **Stephen A. Campbell**, University of Minnesota, Tel 612-625-5876, Fax 612-625-4583, campbell@ece.umn.edu; **Brad Herner**, Applied Materials, Tel 408-748-5619, Fax 408-235-4626, brad_herner@amat.com; **Jorge Kittl**, Texas Instruments, Tel 972-995-6841, Fax 972-995-1916, kittl@spdc.ti.com; **Paul R. Besser**, Motorola-AMD Alliance Logic Technology, Tel 512-933-6397, Fax 512-933-3356, r7204c@email.sps.mot.com

D: Materials, Technology, and Reliability for Advanced Interconnects and Low-k Dielectrics
Karen Maex, IMEC, Belgium, Tel 32-16-281358, Fax 32-16-281315, karen.maex@imec.be; **Young-Chang Joo**, Seoul National University, Korea, Tel 82-2-8807514, Fax 82-2-8838197, ycjoo@plaza.snu.ac.kr; **Gottlieb S. Oehrlein**, SUNY-Albany, Tel 518-442-4653, Fax 518-442-5260, oehrlein@cnsibm.albany.edu; **Shinichi Ogawa**, Matsushita Electronics Corporation, Japan, Tel 81-75-6628461, Fax 81-75-6626154, shinichi_ogawa@sel.mec.mei.co.jp; **Jeffrey T. Wetzel**, SEMATECH, Tel 512-356-3402, Fax 512-356-3437, jeff.wetzel@sematech.org

E: Fundamentals and Materials Issues in Chemical-Mechanical Polishing of Materials
Rajiv K. Singh, University of Florida, Tel 352-392-1032, Fax 352-846-0326, rsingh@mail.mse.ufl.edu; **Rajeev Bajaj**, Applied Materials, Tel 408-986-7513, Fax 408-563-5430, rajeev_bajaj@amat.com; **Marc Meuris**, IMEC VZW VLSI, Belgium, Tel 32-16-281350, Fax 32-16-281315, meuris@imec.be; **Mansour Moinpour**, Intel Corporation, Tel 408-765-9475, Fax 408-765-2162, mansour.moinpour@intel.com; **Alvaro Maury**, Lucent Technologies, Bell Laboratories, Tel 407-371-7523, Fax 407-371-7566, maury@lucent.com; **Peter Burke**, Rodel Inc., Tel 302-366-0500, Fax 302-366-0187, pburke@rodel.com

F: Magnetic Materials, Structures, and Processing for Information Storage
Mike A. Seigler, Seagate Research, Tel 612-844-7087, Fax 612-844-8595, mike_a_seigler@notes.seagate.com; **Christopher B. Murray**, IBM T.J. Watson Research Center, Tel 914-945-3021, Fax 914-945-2141, cbmurray@us.ibm.com; **Tom P. Nolan** (Consultant), Tel 650-968-8010, tom_p_nolan@yahoo.com; **Shan X. Wang**, Stanford University, Tel 650-723-8671, Fax 650-725-4034, sxwang@ee.stanford.edu; **Brian J. Daniels**, Seagate Recording Heads, Tel 612-844-8377, Fax 612-844-5880, brian_j_daniels@notes.seagate.com

G: Polycrystalline Metal and Magnetic Thin Films
Lynne Gignac, IBM T.J. Watson Research Center, Tel 914-945-3352, Fax 914-945-2141, gignac@us.ibm.com; **Olivier Thomas**, Laboratoire MATOP-UPRESA CNRS, France, Tel 33-491-288672, Fax 33-491-288775, olivier@matop.u-3mrs.fr; **James MacLaren**, Tulane University, Tel 504-865-3171, Fax 504-862-8702, maclaren@mailhost.tcs.tulane.edu; **Bruce Clemens**, Stanford University, Tel 650-725-7455, Fax 650-725-4034, clemens@soe.stanford.edu

H: Corrosion of Metals and Alloys
Nancy Missert, Sandia National Laboratories, Tel 505-844-2234, Fax 505-844-1197, namisse@sandia.gov; **Rudy Buchheit**, The Ohio State University, Tel 614-292-6085, Fax 614-292-9857, buchheit.8@osu.edu; **Mary P. Ryan**, Imperial College of Science Technology and Medicine, United Kingdom, Tel 44-171-5946755, Fax 44-171-5946762, m.p.ryan@ic.ac.uk; **Allison J. Davenport**, The University of Birmingham, United Kingdom, Tel 44-121-4145191, Fax 44-121-4145232, a.davenport@bham.ac.uk

I: New Methods, Mechanisms, and Models of Vapor Deposition
Haydn N. G. Wadley, University of Virginia, Tel 804-924-0816, Fax 804-924-3032, haydn@virginia.edu; **George Gilmer**, Lucent Technologies, Bell Laboratories, Tel 908-582-5547, Fax 908-582-4228, ghg@bell-labs.com; **William Barker**, ITN Energy Systems, Tel 303-285-5105, Fax 303-420-1551, wbarker@itnes.com

J: Laser-Solid Interactions for Materials Processing
David P. Norton, Oak Ridge National Laboratory, Tel 423-574-5965, Fax 423-576-3676, ntr@ornl.gov; **D. Kumar**, University of Florida, Tel 352-846-2246, Fax 352-392-3771, dhkum@mse.ufl.edu; **Clinton B. Lee**, North Carolina A&T State University, Tel 336-334-7760 x-217, Fax 336-334-7716, cbl@ncat.edu; **Kenji Ebihara**, Kumamoto University, Japan, Tel 81-96-3423628, Fax 81-96-3423630, ebihara@eecs.kumamoto-u.ac.jp; **Xiaoxing Xi**, The Pennsylvania State University, Tel 814-863-5350, Fax 814-865-3604, xi@phys.psu.edu

K: Morphological and Compositional Evolution of Heteroepitaxial Semiconductor Thin Films
Albert-Laszlo Barabasi, University of Notre Dame, Tel 219-631-5767, Fax 219-631-5952, alb@nd.edu; **Eric D. Jones**, Sandia National Laboratories, Tel 505-844-8752, Fax 505-844-3211, edjones@sandia.gov; **Joanna Mirecki Millunchick**, University of Michigan, Tel 734-647-8980, Fax 734-763-4788, joannamm@engin.umich.edu

L: Recent Developments in Oxide and Metal Epitaxy—Theory and Experiment
Mark Yeaton, University of Illinois at Urbana-Champaign, Tel 217-244-0582, Fax 217-244-2278, myeaton@uiuc.edu (From January 2000: Institute of Materials Research and Engineering, Singapore, Tel 65-874-8111, Fax 65-872-0784, m-yeaton@imre.org.sg); **Shirley Chiang**, University of California-Davis, Tel 530-752-8538, Fax 530-752-4717, chiang@physics.ucdavis.edu; **Robin F. C. Farrow**, IBM Almaden Research Center, Tel 408-927-2389, Fax 408-927-2100, farrow@almaden.ibm.com; **James W. Evans**, Iowa State University Ames Lab, Tel 515-294-1638, Fax 515-294-0266, evans@ameslab.gov; **Orlando Auciello**, Argonne National Laboratory, Tel 630-252-1685, Fax 630-252-4798, auciello@anl.gov

M: Morphology and Dynamics of Crystal Surfaces in Complex Molecular Systems
Jim De Yoreo, Lawrence Livermore National Laboratory, Tel 925-423-4240, Fax 925-423-9242, deyoreo1@llnl.gov; **Bill Casey**, University of California-Davis, Tel 530-752-3211, Fax 530-752-1552, whcasey@ucdavis.edu; **Alex Malkin**, University of California-Irvine, Tel 949-824-4397, Fax 949-824-1954, amalkin@uci.edu; **Elias Vlieg**, University of Nijmegen, The Netherlands, Tel 31-24-3653070, Fax 31-24-3653067, vlieg@sci.kun.nl; **Mike Ward**, University of Minnesota, Tel 612-625-3062, Fax 612-626-7246, wardx004@tc.umn.edu

N: Materials for Separations in Analytical Chemistry

Deon Anex, Sandia National Laboratories, Tel 925-294-3644, Fax 925-294-1489, dsanex@sandia.gov; **Frantisek Svec**, University of California-Berkeley, Tel 510-643-1460, Fax 510-643-3079, svec@uclink4.berkeley.edu; **Rajeev Dadoo**, Genentech, Inc., Tel 650-225-7865, Fax 650-225-7060, rdadoo@gene.com

O: Materials Computation—Progress Towards Technological Impact

Ellen B. Stechel, Ford Motor Company, Tel 313-248-5635, Fax 313-322-7044, estechel@ford.com; **Kenneth C. Hass**, Ford Motor Company, Tel 313-322-0098, Fax 313-322-7044, khass1@ford.com; **Gerbrand Ceder**, Massachusetts Institute of Technology, Tel 617-253-1581, Fax 617-258-6534, gerd@lanai.mit.edu; **Stephen M. Foiles**, Sandia National Laboratories, Tel 925-294-2898, Fax 925-294-3231, foiles@sandia.gov; **James Warren**, NIST, Tel 301-975-5708, Fax 301-975-4553, jwarren@nist.gov

P: Multiscale Modeling of Organic Materials

R. Pachter, Air Force Research Laboratory, Tel 937-255-3808, x-3177, Fax 937-255-1128, ruth.pachter@afri.af.mil; **B. Farmer**, Air Force Research Laboratory, Tel 937-255-9209, Fax 937-255-9157, barry.farmer@afri.af.mil; **S. S. Patnaik**, Air Force Research Laboratory, Tel 937-255-6671 x-3116, Fax 937-255-1128, soumya.patnaik@afri.af.mil; **D. Rigby**, Molecular Simulations, Inc., Tel 619-799-5596, Fax 619-458-0136, david@msi.com; **K. Tashiro**, Osaka University, Japan, Tel 81-6-68505455, Fax 81-6-68505453, ktashiro@chem.sci.osaka-u.ac.jp

Q: Flat-Panel Display Materials

Paul Holloway, University of Florida, Tel 352-846-3330, Fax 352-392-4911, pholl@mse.ufl.edu; **Troy Trottier**, Motorola Inc., Tel 602-755-5332, Fax 602-755-5055, gt14120@mail.mot.com; **James Im**, Columbia University, Tel 212-854-8341, Fax 212-854-9010, ji12@columbia.edu; **Sey-Shing Sun**, Planar System, Inc., Tel 503-748-7286, Fax 503-690-6995, sey-shing_sun@planar.com

R: Electron-Emissive Materials and Vacuum Microelectronics

Kevin L. Jensen, Naval Research Laboratory, Tel 202-767-3114, Fax 202-767-1280, kevin.jensen@nrl.navy.mil; **Dorota Temple**, MCNC, Tel 919-248-1945, Fax 919-248-1455, temple@mcnc.org; **William Mackie**, Linfield Research Institute, Tel 503-434-2432, Fax 503-434-2588, billm@linfield.edu; **Robert Nemanich**, North Carolina State University, Tel 919-515-3225, Fax 919-515-7331, robert_nemanich@ncsu.edu; **Junji Itoh**, Electrotechnical Laboratory, Japan, Tel 81-298-545503, Fax 81-298-545507, jitoh@etl.go.jp

S: Electrically Active Polymers

Zhenan Bao, Lucent Technologies, Bell Labs Innovations, Tel 908-582-4716, Fax 908-582-4868, zbao@bell-labs.com; **Mary Galvin**, University of Delaware, Tel 302-831-0873, Fax 302-831-4545, megalvin@udel.edu; **John Reynolds**, University of Florida, Tel 352-392-9151, Fax 352-392-9741, reynolds@chem.ufl.edu; **Lewis Rothberg**, University of Rochester, Tel 716-273-4725, Fax 716-242-9485, ljr@chem.chem.rochester.edu

T: Wide-Bandgap Electronic Devices

Randy J. Shul, Sandia National Laboratories, Tel 505-844-6126, Fax 505-844-8985, rjshul@sandia.gov; **Fan Ren**, University of Florida, Tel 352-392-4727, Fax 352-392-3235, ren@che.ufl.edu; **Masanori Murakami**, Kyoto University, Japan, Tel 81-75-7535466, Fax 81-75-7535478, murakami@mtl.kyoto-u.ac.jp; **Wilfried Pletschen**, Fraunhofer-IAF, Germany, Tel 49-761-5159343, Fax 49-761-5159219, pletschen@iaf.fhg.de

U: Materials Science of Novel Oxide-Based Electronics

David S. Ginley, NREL, Tel 303-384-6573, Fax 303-384-6430, david_ginley@nrel.gov; **D. M. News**, IBM T.J. Watson Research Center, Tel 914-945-3551, Fax 914-945-2141, dmnews@watson.ibm.com; **H. Kawazoe**, HOYA Corporation, Japan, Tel 81-42-5462775, Fax 81-42-5462709, kawazoe@rdc.hoya.co.jp; **A. B. Kozyrev**, Electrotechnical University, Russia, Tel/Fax 7-812-234-4809, mlp@eltech.ru; **J. D. Perkins**, NREL, Tel 303-384-6606, Fax 303-384-6430, john_perkins@nrel.gov

V: Materials Development for Direct Write Technologies

Douglas B. Chrisey, Naval Research Laboratory, Tel 202-767-4788, Fax 202-767-5301, chrisey@ccf.nrl.navy.mil; **Daniel R. Gamota**, Motorola Inc., Tel 847-576-5084, Fax 847-576-2111, adg002@email.mot.com; **Henry Helvajian**, Aerospace Corporation, Tel 310-336-7621, Fax 310-336-7680, henry.helvajian@aero.org

W: Combinatorial Chemistry and Materials Science

Bruce van Dover, Lucent Technologies, Bell Labs Innovations, Tel 908-582-6540, Fax 908-582-2521, rbvd@bell-labs.com; **Marty Devenney**, Symyx Technologies, Tel 408-764-2038, Fax 408-748-0175, mdevenney@symyx.com; **Jim Engstrom**, Symyx Technologies, Tel 408-330-2181, Fax 408-748-0175, jengstrom@symyx.com; **Jean Frechet**, University of California-Berkeley, Tel 510-643-3077, Fax 510-643-3079, frechet@cchem.berkeley.edu

X: Frontiers of Materials Research

Anna C. Balazs, University of Pittsburgh, Tel 412-648-9250, Fax 412-624-9639, balazs@vms.cis.pitt.edu; **Robert Q. Hwang**, Sandia National Laboratories, Tel 925-294-1570, Fax 925-294-3231, rghwang@sandia.gov; **Kevin S. Jones**, University of Florida, Tel 352-392-9872, Fax 352-392-8381, kjones@eng.ufl.edu; **Frances M. Ross**, IBM T.J. Watson Research Center, Tel 914-945-1022, Fax 914-945-2141, fmross@us.ibm.com

Y: Solid Freeform and Additive Fabrication III

Duane Dimos, Sandia National Laboratories, Tel 505-844-6385, Fax 505-844-9781, dbdimos@sandia.gov; **Stephen C. Danforth**, Rutgers University, Tel 732-445-2211, Fax 732-445-6699, danforth@rci.rutgers.edu; **Fritz B. Prinz**, Stanford University, Tel 650-723-0084, Fax 650-723-5034, fbp@cdr.stanford.edu

Z: Thermoelectric Materials 2000—The Next-Generation Materials for Small-Scale Refrigeration and Power-Generation Applications

Terry M. Tritt, Clemson University, Tel 864-656-5319, Fax 864-656-0805, ttritt@clemson.edu; **Gerald Mahan**, University of Tennessee, Tel 423-974-8129, Fax 423-974-6378, gmahan@utk.edu; **David Mandrus**, Oak Ridge National Laboratory, Tel 423-576-6282, Fax 423-574-4814, mandrusdg@ornl.gov; **George S. Nolas**, Marlow Industries Inc., Tel 214-503-3363, Fax 214-341-5212, gnolas@marlow.com; **Mercouri G. Kanatzidis**, Michigan State University, Tel 517-355-9715, Fax 517-353-1793, kanatzid@argus.cem.msu.edu

AA: Millimeter/Submillimeter-Wave Technology—Materials, Devices, and Diagnostics

S. K. Sundaram, Pacific Northwest National Laboratory, Tel 509-373-6665, Fax 509-376-3108, sk.sundaram@pnl.gov; **P. P. Woskov**, Massachusetts Institute of Technology, Tel 617-253-8648, Fax 617-258-0700, ppw@psfc.mit.edu; **Yoh-Ichiro "Joe" Ogita**, Kanagawa Institute of Technology, Tel 81-462-913085, Fax 81-462-426089, ogita@ele.kanagawa-it.ac.jp; **Jussi Tuovinen**, Millimetre Wave Laboratory of Finland—MilliLab, Tel 358-9-4566508, Fax 358-9-4567013, jussi.tuovinen@vtt.fi

BB: The Granular State

Surajit Sen, SUNY-Buffalo, Tel 716-645-6314, Fax 716-645-2507, sen@dynamics.physics.buffalo.edu; **Melany Hunt**, California Institute of Technology, Tel 626-395-4231, Fax 626-568-2719, hunt@caltech.edu; **Frank van Swol**, Sandia National Laboratories, Tel 505-272-7440, Fax 505-272-7336, vanswol@unm.edu

CC: Hybrid Organic/Inorganic Materials

Richard M. Laine, University of Michigan, Tel 734-764-6203, Fax 734-763-4788, talsdad@umich.edu; **Clément Sanchez**, Université Pierre et Marie Curie, France, Tel 33-144-275534, Fax 33-144-274769, clems@ccr.jussieu.fr; **Emmanuel Giannelis**, Cornell University, Tel 607-255-9680, Fax 607-255-2365, emmanuel@msc.cornell.edu; **C. Jeffrey Brinker**, Sandia National Laboratories, Tel 505-272-7627, Fax 505-272-7304, cjbrink@sandia.gov

DD: Interfacial Aspects of Soft Biomaterials

Anne M. Mayes, Massachusetts Institute of Technology, Tel 617-253-3318, Fax 617-258-6534, amayes@mit.edu; **Annelise E. Barron**, Northwestern University, Tel 847-491-2778, Fax 847-491-3728, a-barron@nwu.edu; **Samuel I. Stupp**, Northwestern University, Tel 847-491-3002, Fax 847-491-3010, s-stupp@nwu.edu; **Buddy D. Ratner**, University of Washington, Tel 206-685-1005, Fax 206-616-9763, ratner@uweb.engr.washington.edu

EE: Nanostructures in Polymers

Peter F. Green, The University of Texas-Austin, Tel 512-471-3188, Fax 512-471-7681, green@che.utexas.edu; **Thomas P. Russell**, University of Massachusetts-Amherst, Tel 413-577-1516, Fax 413-577-1510 or -545-0082, russell@iskra.pse.umass.edu

FF: Interfaces, Adhesion, and Processing in Polymer Systems

Spiros H. Anastasiadis, Foundation for Research and Technology-Hellas, Tel 30-81-391466, Fax 30-81-391305, spiros@iesl.forth.gr; **Alamgir Karim**, National Institute of Standards and Technology, Tel 301-975-6588, Fax 301-975-4924, karim@email.nist.gov; **Gregory S. Ferguson**, Lehigh University, Tel 610-758-3462, Fax 610-758-6536, gf03@lehigh.edu

GG: When Materials Matter—Analyzing, Predicting, and Preventing Disasters

Marcel Ausloos, Université de Liège, Tel 32-4-3663752, Fax 32-4-3662990, ausloos@gw.unipic.ulg.ac.be; **Michael Marder**, University of Texas, Tel 512-232-2773, Fax 512-471-1558, marder@chaos.ph.utexas.edu; **Alan J. Hurd**, Sandia National Laboratories, Tel 505-272-7642, Fax 505-272-7304, ajhurd@sandia.gov

HH: Materials Science and Engineering Education in the New Millennium

Blair London, California Polytechnic State University, Tel 805-756-2536, Fax 805-756-2299, blondon@calpoly.edu; **Emily Allen**, San Jose State University, Tel 408-924-4010, Fax 408-924-4057, elallen@email.sjsu.edu; **Amy Moll**, Hewlett-Packard Company, Tel 719-590-3307, Fax 719-590-3525, amy_moll@hp.com; **David Pope**, The University of Pennsylvania, Tel 215-898-9837, Fax 215-573-2128, pope@eniach.seas.upenn.edu

For additional meeting information, contact:



MATERIALS RESEARCH SOCIETY

506 Keystone Drive, Warrendale, PA 15086-7573
Tel 724-779-3003 • Fax 724-779-8313

E-mail: info@mrs.org • MRS Web site: www.mrs.org